


<b>Search Notes</b> 	<b>Application/Control No.</b> 10523309	<b>Applicant(s)/Patent Under Reexamination</b> HENNE ET AL.
	<b>Examiner</b> Kaplan, Hal I	<b>Art Unit</b> 2836

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
307	100	1/22/2008	HK

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TDB) - See Search History Printout	1/22/2008	HK
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TDB) - See Search History Printout	1/23/2008	HK

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>